

Resource Summary Report

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Jeol: JEM-2100 Electron Microscope

RRID:SCR_028490

Type: Tool

Proper Citation

Jeol: JEM-2100 Electron Microscope (RRID:SCR_028490)

Resource Information

URL: <https://www.jeol.com/products/scientific/tem/JEM-2100.php>

Proper Citation: Jeol: JEM-2100 Electron Microscope (RRID:SCR_028490)

Description: JEOL JEM-2100 is a versatile, 200 kV transmission electron microscope (TEM) designed for high-resolution imaging and structural analysis across materials, nanotechnology, and biological sciences. It allows researchers to visualize nanoscale structures, perform chemical composition mapping, and analyze atomic crystal lattices.

Synonyms: , JEM-2100, JEM-2100 Electron Microscope, JEOL JEM-2100

Resource Type: instrument resource

Keywords: Japan Electron Optics Laboratory, transmission electron microscope,

Specification URL: https://raw.githubusercontent.com/SciCrunch/RRID-Instruments/refs/heads/main/PDF/SCR_028490.pdf

Resource Name: Jeol: JEM-2100 Electron Microscope

Resource ID: SCR_028490

Alternate IDs: Model_Number_JEOL_JEM-2100

Record Creation Time: 20260529T042811+0000

Record Last Update: 20260808T190830+0000

Ratings and Alerts

No rating or validation information has been found for Jeol: JEM-2100 Electron Microscope.

No alerts have been found for Jeol: JEM-2100 Electron Microscope.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.